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December 2014

## FCP260N60E / FCPF260N60E N-Channel SuperFET® II Easy-Drive MOSFET

**600 V, 15 A, 260 m**Ω

#### **Features**

- 650 V @ T<sub>J</sub> = 150°C
- Typ.  $R_{DS(on)}$  = 220  $m\Omega$
- Ultra Low Gate Charge (Typ. Q<sub>q</sub> = 48 nC)
- Low Effective Output Capacitance (Typ. Coss(eff.) = 129 pF)
- 100% Avalanche Tested
- · An Integrated Gate Resistor
- · RoHS Compliant

#### **Applications**

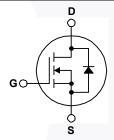
- · LCD / LED / PDP TV Lighting
- · Solar Inverter
- · AC-DC Power Supply

#### Description

SuperFET® II MOSFET is Fairchild Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This technology is tailored to minimize conduction loss, provide superior switching performance, dv/dt rate and higher avalanche energy. Consequently, SuperFET II MOSFET easy-drive series offers slightly slower rise and fall times compared to the SuperFET II MOSFET series. Noted by the "E" part number suffix, this family helps manage EMI issues and allows for easier design implementation. For faster switching in applications where switching losses must be at an absolute minimum, please consider the SuperFET II MOSFET series.







#### **MOSFET Maximum Ratings** T<sub>C</sub> = 25°C unless otherwise noted.

Symbol		Parameter		FCP260N60E	FCPF260N60E	Unit	
$V_{DSS}$	Drain to Source Voltage					V	
V	Cata ta Sauraa Valtaga	- DC		±	20	V	
$V_{GSS}$	Gate to Source Voltage	- AC	(f > 1 Hz)	±	30	V	
	Drain Current	- Continuous (T <sub>C</sub> = 25°C)		15 15*			
ID	Drain Current	- Continuous (T <sub>C</sub> = 100°C)		9.5	9.5*	Α	
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	45	45*	Α	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		292.5		mJ		
I <sub>AR</sub>	Avalanche Current (Note 1)		(Note 1)	3.0		Α	
E <sub>AR</sub>	Repetitive Avalanche Energy		(Note 1)	1.56		mJ	
dv/dt	MOSFET dv/dt			100		1//	
dv/dt	Peak Diode Recovery dv/dt (Note 3		(Note 3)	2	20	V/ns	
Б	Dawer Dissipation	$(T_C = 25^{\circ}C)$		156	36	W	
$P_{D}$	Power Dissipation  - Derate Above 25°C		15	1.25 0.29		W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Tempe	rature Range	ture Range		+150	°С	
TL	Maximum Lead Temperature f	or Soldering, 1/8" from Case for	5 Seconds	3	00	°С	

#### \*Drain current limited by maximum junction temperature.

#### **Thermal Characteristics**

Symbol	Parameter	FCP260N60E	FCPF260N60E	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.8	3.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	62.5	5/88

### **Package Marking and Ordering Information**

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FCP260N60E	FCP260N60E	TO-220	Tube	N/A	N/A	50 units
FCPF260N60E	FCPF260N60E	TO-220F	Tube	N/A	N/A	50 units

**Test Conditions** 

Min.

Тур.

Max.

Unit

### **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted. Parameter

Off Chara	acteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 10 \text{ mA}, T_J = 25^{\circ}\text{C}$	600	-	-	V
		$V_{GS} = 0 \text{ V}, I_D = 10 \text{ mA}, T_J = 150^{\circ}\text{C}$	650	-	-	
ΔBV <sub>DSS</sub> / ΔT <sub>J</sub>	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 10 mA, Referenced to 25°C	-	0.67	-	V/°C
BV <sub>DS</sub>	Drain to Source Avalanche Breakdown Voltage	V <sub>GS</sub> = 0 V, I <sub>D</sub> = 15 A	-	700	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V	-	-	1	
		$V_{DS} = 480 \text{ V}, T_{C} = 125^{\circ}\text{C}$	-	2.6	-	μА
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$	-	-	±100	nA

#### **On Characteristics**

Symbol

V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	2.5	-	3.5	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 7.5 \text{ A}$	-	0.22	0.26	Ω
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 20 \text{ V}, I_{D} = 7.5 \text{ A}$	1	15.5	1	S

#### **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V 05.V.V 0.V	-	1880	2500	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1 MHz	-	1330	1770	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 WII 12	-	85	130	pF
C <sub>oss</sub>	Output Capacitance	$V_{DS} = 380 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$	-	32	-	pF
C <sub>oss(eff.)</sub>	Effective Output Capacitance	$V_{DS} = 0 V \text{ to } 480 V, V_{GS} = 0 V$	-	129	-	pF
$Q_{g(tot)}$	Total Gate Charge at 10V	$V_{DS} = 380 \text{ V}, I_{D} = 7.5 \text{ A},$	-	48	62	nC
$Q_{gs}$	Gate to Source Gate Charge	V <sub>GS</sub> = 10 V	-	7.4	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	(Note 4)	- /	17	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	- /	5.8	-	Ω

#### **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		// -	20	50	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 380 \text{ V}, I_D = 7.5 \text{ A},$	-	11	32	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{G} = 4.7 \Omega$	-	89	188	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	-	13	36	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current			-	15	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current			-	45	Α
$V_{SD}$	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 7.5 A		-	-	1.2	V
t <sub>rr</sub>	Reverse Recovery Time	/ <sub>GS</sub> = 0 V, I <sub>SD</sub> = 7.5 A,	-	270	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge d	$H_F/dt = 100 A/\mu s$	-	3.6	-	μС

- ${\it 1. Repetitive\ rating: pulse-width\ limited\ by\ maximum\ junction\ temperature.}$
- 2. I<sub>AS</sub> = 3 A, V<sub>DD</sub> = 50 V, R<sub>G</sub> = 25  $\Omega$ , starting T<sub>J</sub> = 25°C.
- 3.  $I_{SD} \le 7.5$  A, di/dt  $\le 200$  A/ $\mu$ s,  $V_{DD} \le BV_{DSS}$ , starting  $T_J$  = 25°C.
- 4. Essentially independent of operating temperature typical characteristics.

#### **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

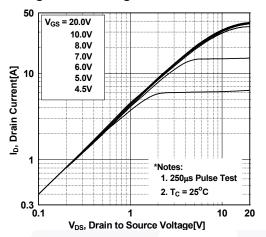


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

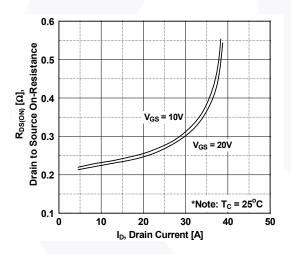


Figure 5. Capacitance Characteristics

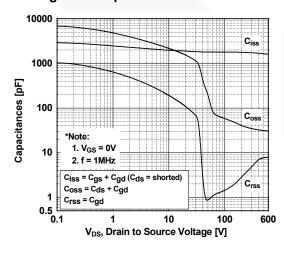


Figure 2. Transfer Characteristics

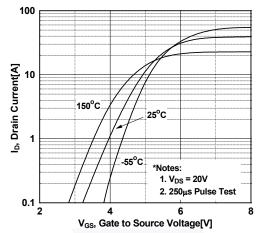


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

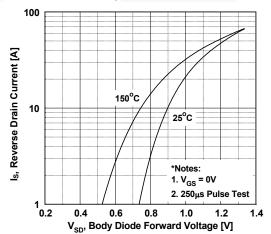
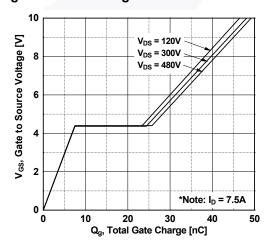


Figure 6. Gate Charge Characteristics



#### **Typical Performance Characteristics** (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

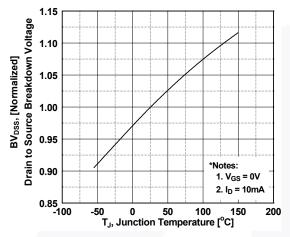


Figure 9. Maximum Safe Operating Area for FCP260N60E

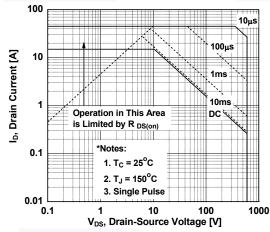


Figure 11. Maximum Drain Current vs. Case Temperature

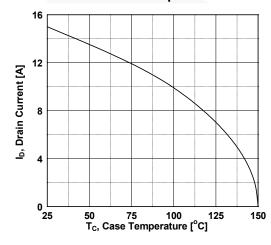


Figure 8. On-Resistance Variation vs. Temperature

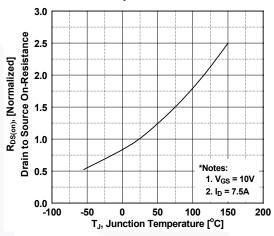


Figure 10. Maximum Safe Operating Area for FCPF260N60E

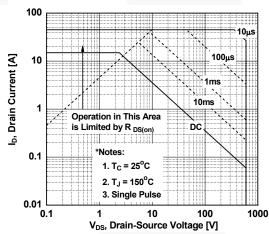
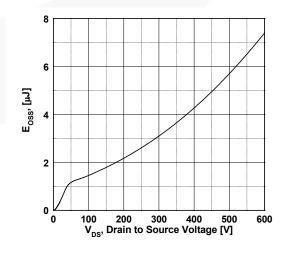


Figure 12. Eoss vs. Drain to Source Voltage



#### **Typical Performance Characteristics** (Continued)

Figure 13. Transient Thermal Response Curve for FCP260N60E

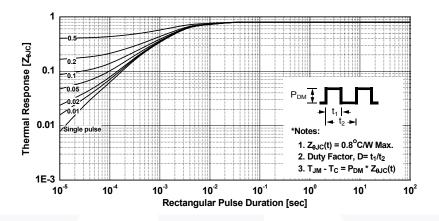
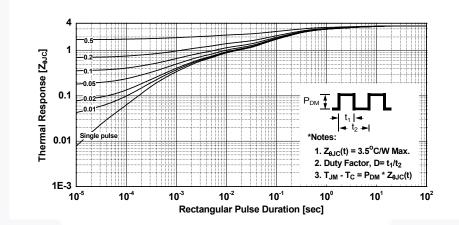


Figure 14. Transient Thermal Response Curve for FCPF260N60E



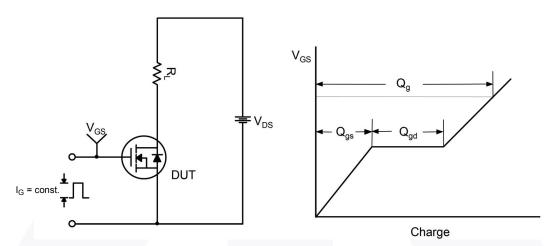


Figure 15. Gate Charge Test Circuit & Waveform

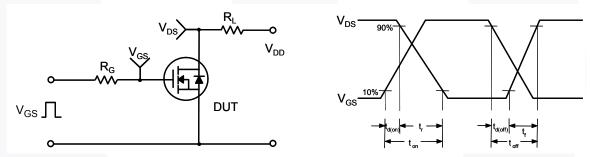


Figure 16. Resistive Switching Test Circuit & Waveforms

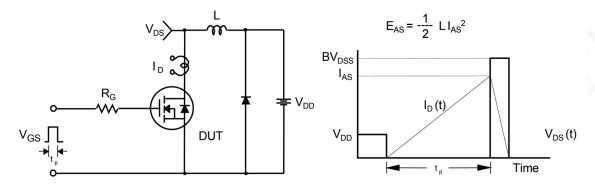


Figure 17. Unclamped Inductive Switching Test Circuit & Waveforms

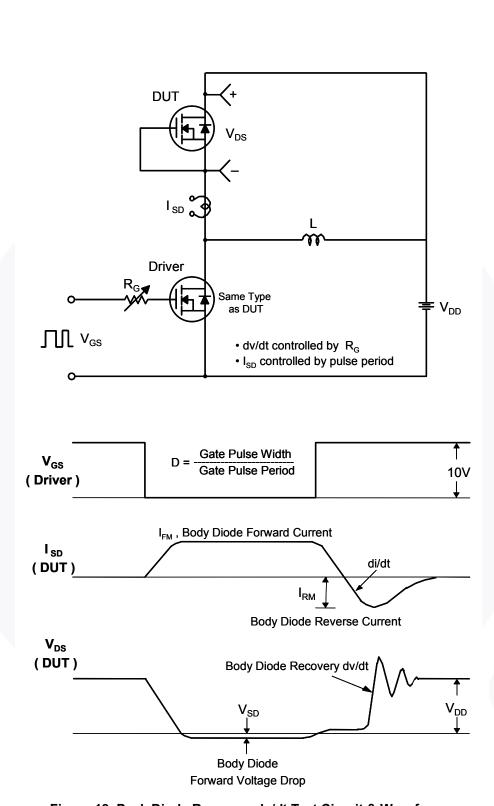
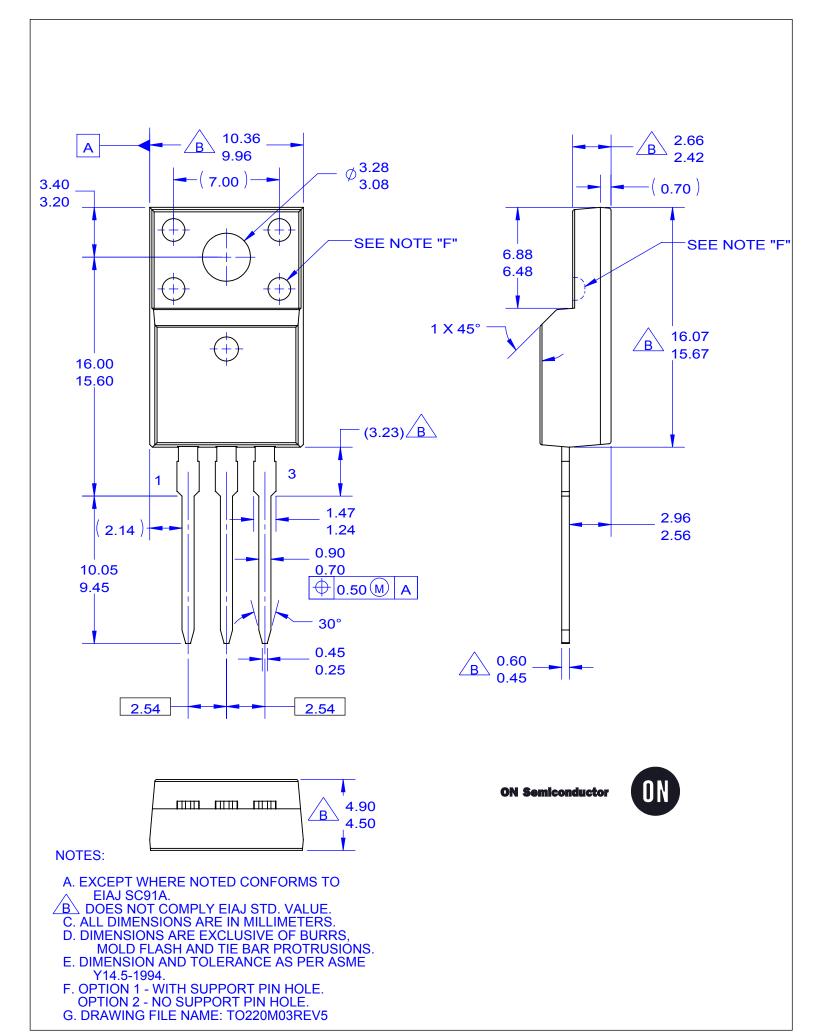


Figure 18. Peak Diode Recovery dv/dt Test Circuit & Waveforms





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